Notice of References Cited Reexamination CARR, JEFFREY W. Examiner Allan W. Olsen Reexamination CARR, JEFFREY W. Art Unit Page 1 of 1

Application/Control No.

Applicant(s)/Patent Under

U.S. PATENT DOCUMENTS

*	·	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

	TOW FAILURE BOOKING							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U	ZAROWIN et al. Rapid Non-contact, damage free shaping of Optical & Other Surfaces with Plasma Assisted Chemical Etching, 43rd Annual Symposium on Frequency Control 1989, 623-626.						
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	х							

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